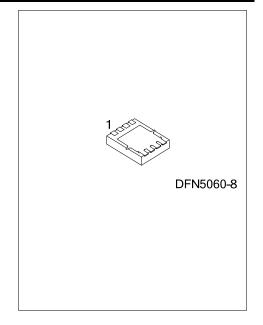
UNA10R160M POWER MOSFET

60A, 100V N-CHANNEL ENHANCEMENT MODE TRENCH POWER MOSFET

DESCRIPTION

The UTC **UNA10R160M** is N-channel enhancement mode power MOSFET using UTC's advanced technology to provide customers with high switching speed, a extremely low $R_{\text{DS}(\text{ON})}$ and low gate charge.

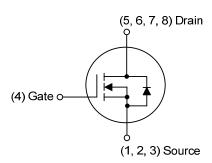
The UTC **UNA10R160M** is suitable for high frequency Point -of-Load Synchronous, Networking DC-DC System, CCFL Back-light Inverter, etc.



■ FEATURES

- * $R_{DS(ON)}$ < 16 m Ω @ V_{GS} =10V, I_{D} =25A $R_{DS(ON)}$ < 18 m Ω @ V_{GS} =4.5V, I_{D} =12A
- * Green Device Available
- * Low Gate Charge
- * Surface mount package

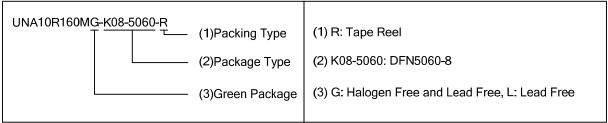
■ SYMBOL



■ ORDERING INFORMATION

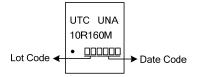
	Ordering Number		Dookogo	Pin Assignment							Dooking	
	Lead Free	Halogen Free	Package	1	2	3	4	5	6	7	8	Packing
L	JNA10R160ML-K08-5060-R	UNA10R160MG-K08-5060-R	DFN5060-8	S	S	S	G	D	D	D	D	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source



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MARKING



UNA10R160M POWER MOSFET

■ ABSOLUTE MAXIMUM RATING (T_C =25°C, unless otherwise specified)

PARAME	TER	SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	100	V
Gate-Source Voltage		V_{GSS}	±20	V
Drain Current	Continuous	I _D	60	Α
Drain Current	Pulsed (Note 2)	I _{DM}	240	Α
Avalanche Energy (Note 3)		E _{AS}	63	mJ
Peak Diode Recovery dv/dt	(Note 4)	dv/dt	1.6	V/ns
Power Dissipation		P_{D}	88	W
Junction Temperature		T_J	+150	°C
Storage Temperature Range	9	T _{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Pulse width limited by safe operating area.
- 3. L=0.1mH, I_{AS} =35.5A, V_{DD} =20V, R_{G} =25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 4. I_{SD} ≤30A, di/dt≤200A/ μ s, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	40.3	°C/W
Junction to Case	θ_{JC}	1.4	°C/W

Note: The data tested by surface mounted on a 1 inch² FR-4 board with 2 oz copper.

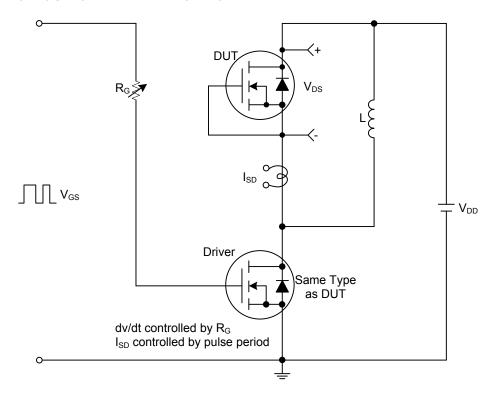
■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MAX	UNIT							
OFF CHARACTERISTICS											
Drain-Source Breakdown Voltage	BV _{DSS}	$I_D=250\mu A, V_{GS}=0V$	100			V					
Drain-Source Leakage Current	I _{DSS}	V _{DS} =100V, V _{GS} =0V,T _J =25°C		1	μΑ						
Gate-Source Leakage Current		V_{GS} =+20V, V_{DS} =0V			+100	nA					
Reverse	I_{GSS}	V _{GS} =-20V, V _{DS} =0V			-100	nA					
ON CHARACTERISTICS											
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$		3.0	V						
Static Drain-Source On-State Resistance	D	V_{GS} =10V, I_D =25A			16	mΩ					
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =12A			18	mΩ					
DYNAMIC PARAMETERS											
Input Capacitance	C _{ISS}			6800		рF					
Output Capacitance	Coss	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		320		рF					
Reverse Transfer Capacitance	C _{RSS}			190		рF					
SWITCHING PARAMETERS											
Total Gate Charge (Note 1)	Q_{G}	\/ -90\/ \/ -10\/ -50A		82		nC					
Gate to Source Charge	Q_{GS}	V_{DS} =80V, V_{GS} =10V, I_{D} =50A I_{G} =1mA (Note1, 2)		32		nC					
Gate to Drain Charge	Q_{GD}	IG-IIIA (Note I, 2)		8		nC					
Turn-on Delay Time (Note 1)	t _{D(ON)}			31.6		ns					
Rise Time	t _R	V_{DS} =50V, V_{GS} =10V, I_{D} =28A,		13.4		ns					
Turn-off Delay Time	t _{D(OFF)}	R _G =25Ω (Note1, 2)		56		ns					
Fall-Time	t _F		10		ns						
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS											
Maximum Body-Diode Continuous Current	Is				60	Α					
Maximum Body-Diode Pulsed Current	I _{SM}				240	Α					
Forward On Voltage (Note 1)	V_{SD}	I _S =50A, V _{GS} =0V			1.2	V					
Reverse Recovery Time (Note 1)	t _{rr}	I _S =30A, V _{GS} =0V,		52		ns					
Reverse Recovery Charge	Q _{rr}	dI/dt=100A/μs		110		nC					

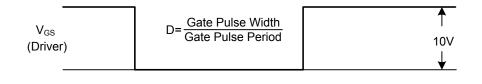
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle≤2%.

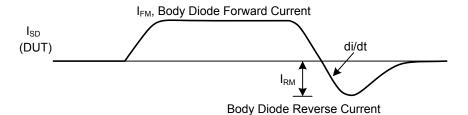
2. Essentially independent of operating temperature.

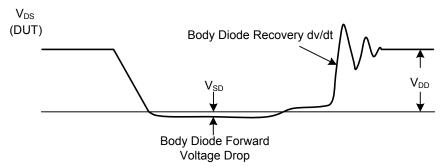
■ TEST CIRCUITS AND WAVEFORMS



Peak Diode Recovery dv/dt Test Circuit



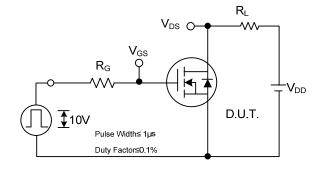


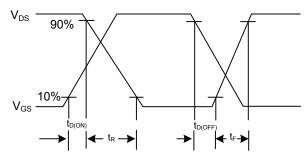


Peak Diode Recovery dv/dt Test Circuit and Waveforms

Peak Diode Recovery dv/dt Waveforms

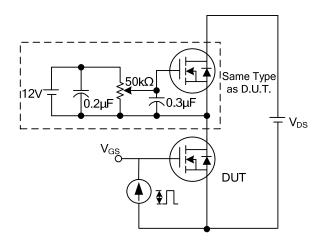
■ TEST CIRCUITS AND WAVEFORMS

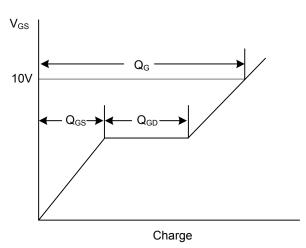




Switching Test Circuit

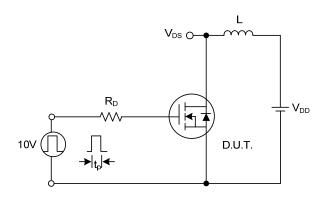
Switching Waveforms

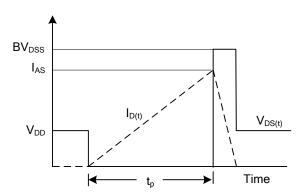




Gate Charge Test Circuit

Gate Charge Waveform





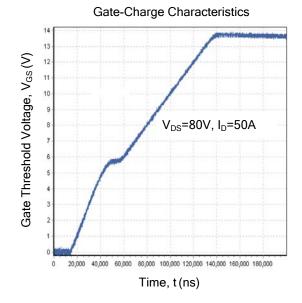
Unclamped Inductive Switching Test Circuit

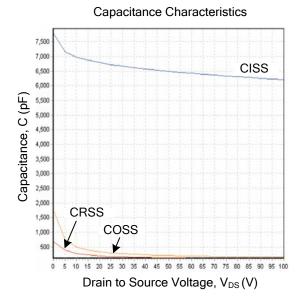
Unclamped Inductive Switching Waveforms

UNA10R160M

POWER MOSFET

■ TYPICAL CHARACTERISTICS





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